

METHODS AND APPARATUS FOR TESTING
OPTICAL AND ELECTRICAL COMPONENTS
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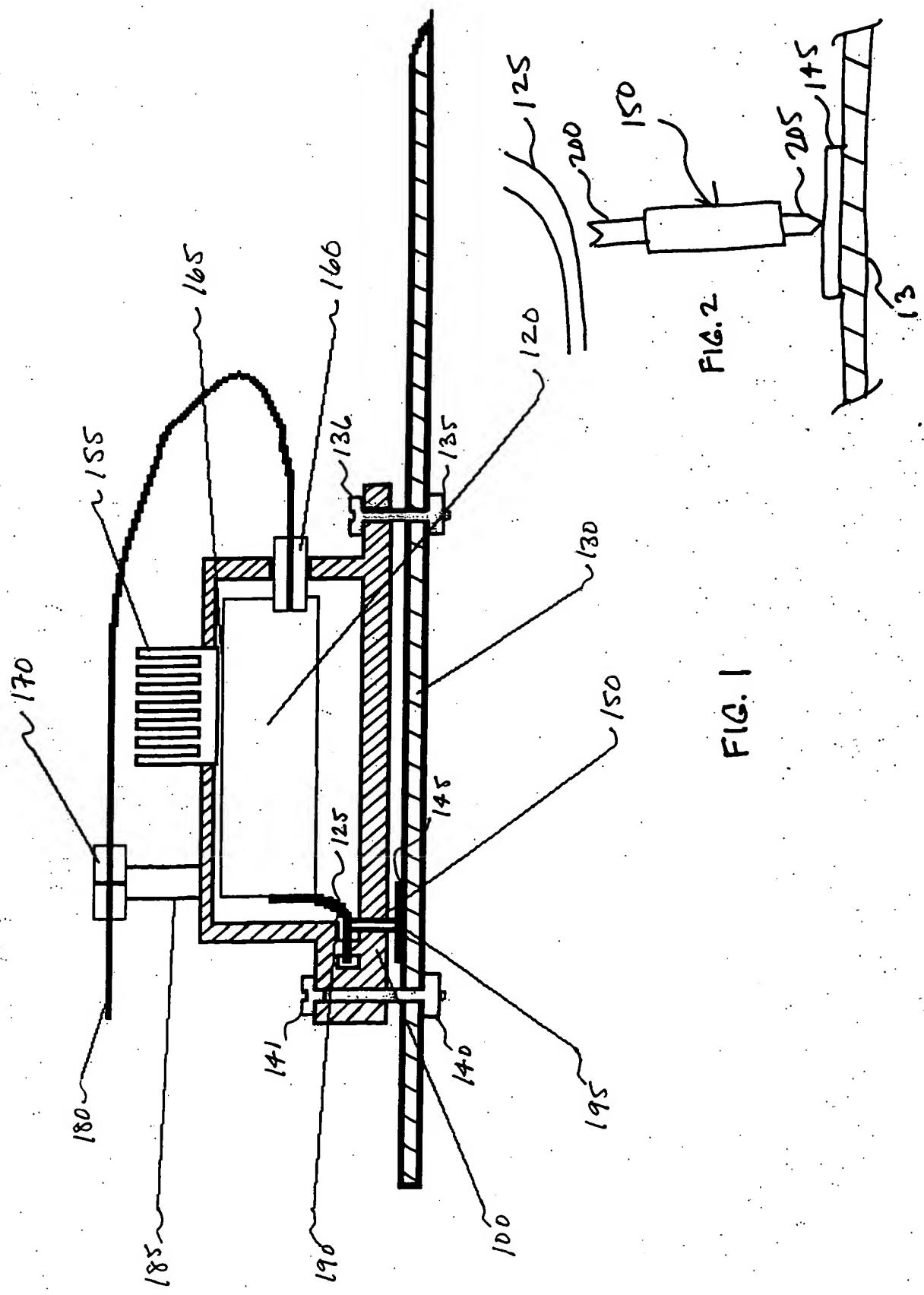


FIG. 1

FIG. 2